

April 1988 Revised October 2000

# 74F521

# 8-Bit Identity Comparator

### **General Description**

The 74F521 is an expandable 8-bit comparator. It compares two words of up to eight bits each and provides a LOW output when the two words match bit for bit. The expansion input  $\overline{I}_{A=B}$  also serves as an active LOW enable input.

#### **Features**

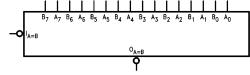
- Compares two 8-bit words in 6.5 ns typ
- Expandable to any word length
- 20-pin package

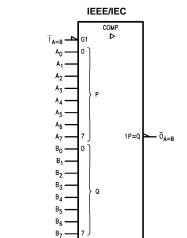
## **Ordering Code:**

Order Number	Package Number	Package Description				
74F521SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide				
74F521SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide				
74F521MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide				
74F521PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide				

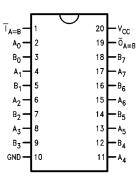
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

### **Logic Symbols**





## **Connection Diagram**



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DS009545

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# **Unit Loading/Fan Out**

Pin Names	De a minetia m	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
A <sub>0</sub> -A <sub>7</sub>	Word A Inputs	1.0/1.0	20 μA/-0.6 mA	
B <sub>0</sub> -B <sub>7</sub>	Word B Inputs	1.0/1.0	20 μA/–0.6 mA	
$\overline{I}_{A=B}$	Expansion or Enable Input (Active LOW)	1.0/1.0	20 μA/–0.6 mA	
$\overline{O}_{A=B}$	Identity Output (Active LOW)	50/33.3	−1 mA/20 mA	

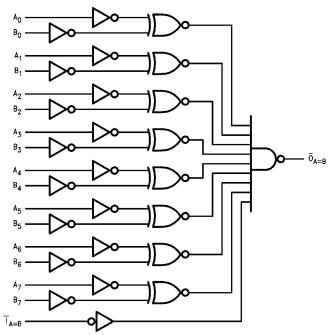
## **Truth Table**

İr	Output			
Ī <sub>A = B</sub>	$\bar{I}_{A=B}$ A, B			
L	A = B (Note 1)	L		
L	$A \neq B$	Н		
Н	A = B (Note 1)	Н		
н	$A \neq B$	Н		

H = HIGH Voltage Level L = LOW Voltage Level

Note 1:  $A_0 = B_0$ ,  $A_1 = B_1$ ,  $A_2 = B_2$ , etc.

## **Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

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## Absolute Maximum Ratings(Note 2)

Storage Temperature -65°C to +150°C -55°C to +125°C Ambient Temperature under Bias

Junction Temperature under Bias -55°C to +150°C

V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 3) -0.5V to +7.0VInput Current (Note 3) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ -0.5V to +5.5V

3-STATE Output

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA)

## **Recommended Operating Conditions**

0°C to +70°C Free Air Ambient Temperature Supply Voltage +4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

### **DC Electrical Characteristics**

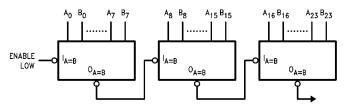
Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage			8.0	V		Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA	
V <sub>OH</sub>	Output HIGH 10% V <sub>CC</sub>	2.5			V	Min	I <sub>OH</sub> = -1 mA	
	Voltage 5% V <sub>CC</sub>	2.7			•	IVIIII	$I_{OH} = -1 \text{ mA}$	
V <sub>OL</sub>	Output LOW 10% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 20 mA	
	Voltage			0.5	V	IVIIII	IOL – 20 IIIA	
I <sub>IH</sub>	Input HIGH Current			5.0	μΑ	Max	V <sub>IN</sub> = 2.7V	
I <sub>BVI</sub>	Input HIGH Current			7.0	μА	Max	V <sub>IN</sub> = 7.0V	
	Breakdown Test			7.0	μΛ	IVIAA	VIN = 7.0V	
I <sub>CEX</sub>	Output HIGH			50	μА	Max	V <sub>OUT</sub> = V <sub>CC</sub>	
	Leakage Current			30	μΛ	IVIAA	VOUT - VCC	
V <sub>ID</sub>	Input Leakage	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA	
	Test	4.75			•	0.0	All Other Pins Grounded	
I <sub>OD</sub>	Output Leakage			3.75	μА	0.0	V <sub>IOD</sub> = 150 mV	
	Circuit Current			3.73	μΛ	0.0	All Other Pins Grounded	
I <sub>IL</sub>	Input LOW Current			-0.6	mA	Max	V <sub>IN</sub> = 0.5V	
Ios	Output Short-Circuit Current	-60		-150	mA	Max	V <sub>OUT</sub> = 0V	
I <sub>CCH</sub>	Power Supply Current		21	32	mA	Max	V <sub>O</sub> = HIGH	

# **AC Electrical Characteristics**

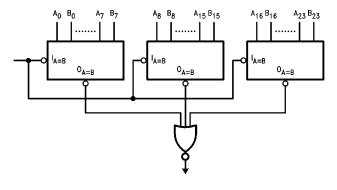
Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	3.0	7.0	10.0	3.0	14.0	3.0	11.0	ns
t <sub>PHL</sub>	$A_n$ or $B_n$ to $\overline{O}_{A=B}$	4.5	7.0	10.0	4.0	15.0	4.0	11.0	
t <sub>PLH</sub>	Propagation Delay	3.0	5.0	6.5	3.0	8.5	3.0	7.5	ns
t <sub>PHL</sub>	$\overline{I}_{A=B}$ to $\overline{O}_{A=B}$	3.5	6.5	9.0	3.5	13.5	3.5	10.0	

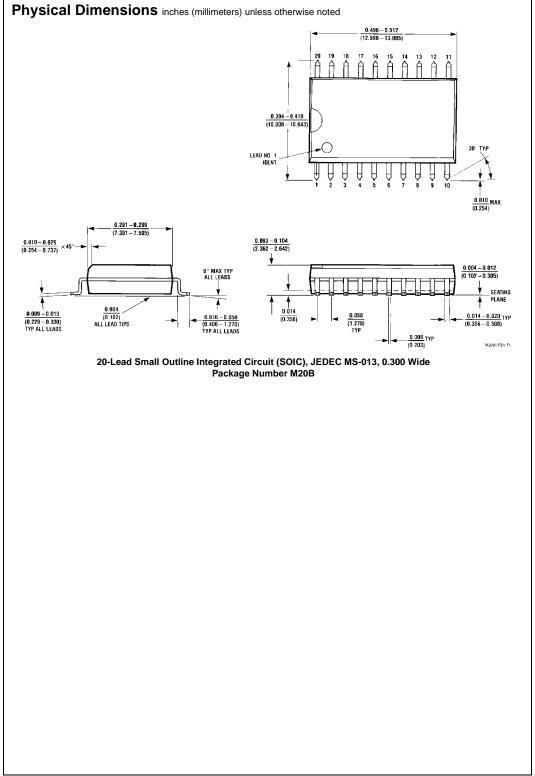
# **Applications**

### Ripple Expansion

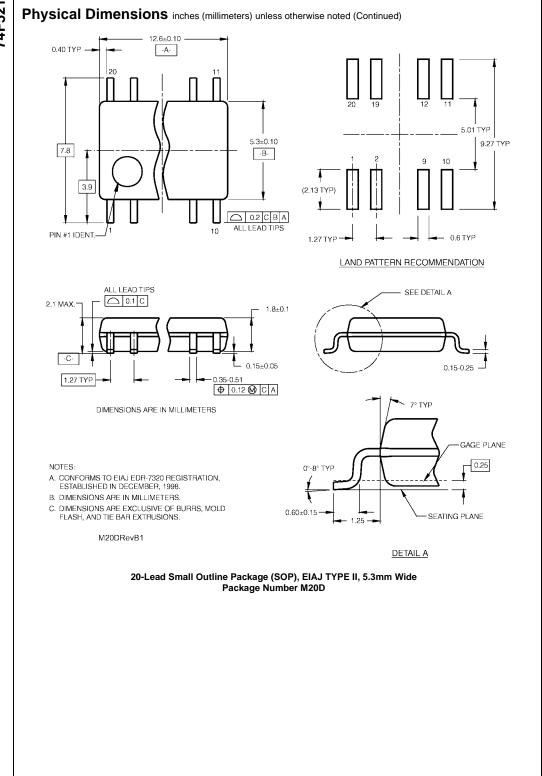


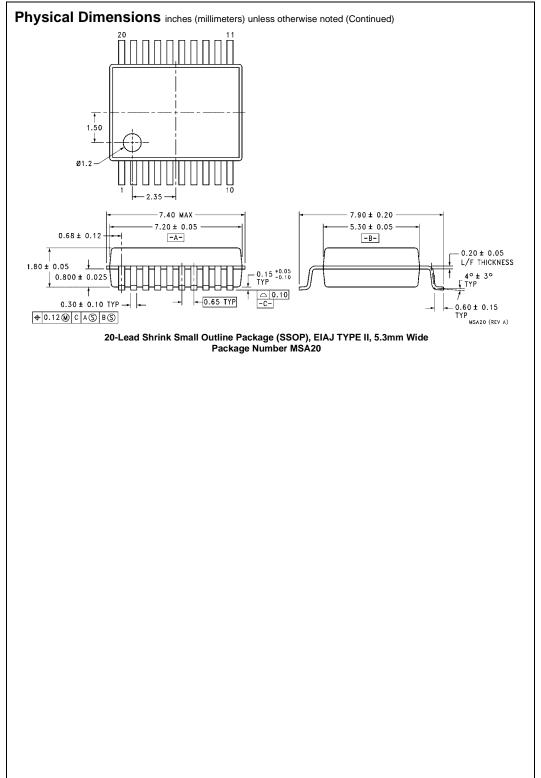
#### Parallel Expansion



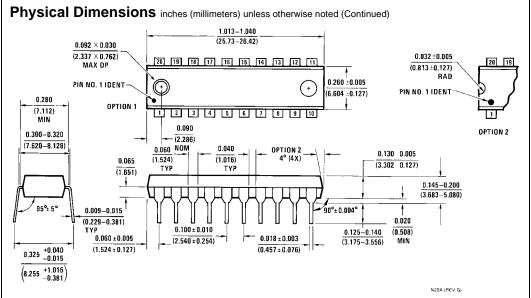


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20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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